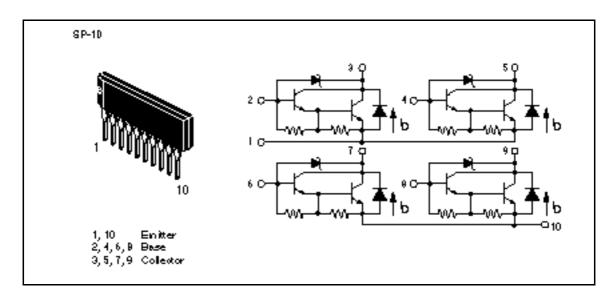
Silicon NPN Triple Diffused

HITACHI

Application

Low frequency power amplifier

Outline





Absolute Maximum Ratings (for each device, $Ta = 25^{\circ}C$)

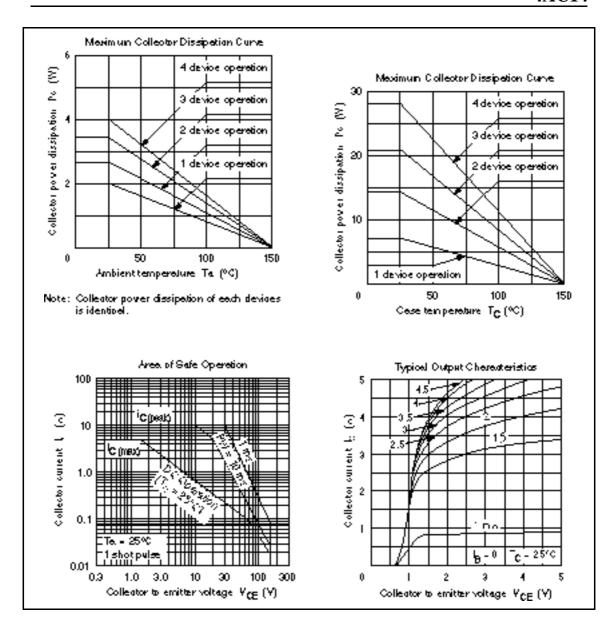
Item	Symbol	Ratings	Unit	
Collector to base voltage	V_{CBO}	150	V	
Collector to emitter voltage	V_{CEO}	150	V	
Emitter to base voltage	V_{EBO}	7	V	
Collector current	I _c	5	A	
Collector peak current	I _{C(peak)}	10	A	
Diode current	I _D	5	A	
Collector power dissipation	P _c *1	4	W	
	$P_{\rm C}^{*1} (T_{\rm C} = 25^{\circ} C)$	28		
Junction temperature	Tj	150	°C	
Storage temperature	Tstg	-55 to +150	°C	

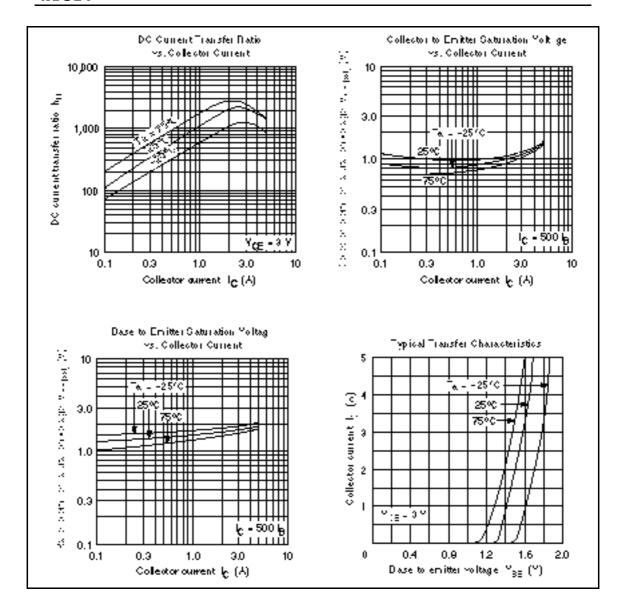
Note: 1. 4 devices operation.

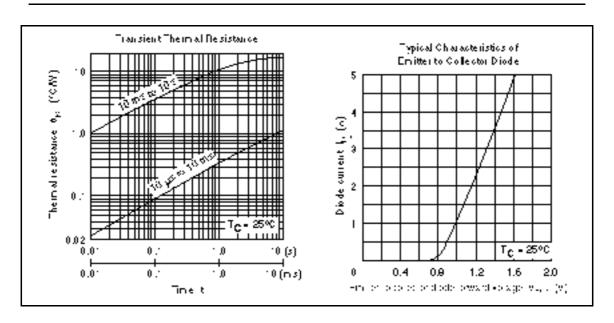
Electrical Characteristics (for each device, $Ta = 25^{\circ}C$)

Item	Symbol	Min	Тур	Max	Unit	Test conditions
Collector to emitter breakdown voltage	$V_{(BR)CBO}$	150	_	_	V	$I_{c} = 0.1 \text{ mA}, I_{E} = 0$
Collector to emitter sustain voltage	$V_{\text{CEO(SUS)}}$	150	_	_	V	$I_{C} = 0.2 \text{ A}, L = 20 \text{ mHz}, R_{BE} =$
Emitter to base breakdown voltage	$V_{(BR)EBO}$	7	_	_	V	$I_{\rm E} = 50 \text{ mA}, I_{\rm C} = 0$
Collector cutoff current	I _{CBO}	_	_	10	μΑ	$V_{CB} = 120 \text{ V}, I_{E} = 0$
	I _{CEO}	_	_	10	_	V _{CE} = 120 V, R _{BE} =
DC current transfer ratio	h _{FE}	1000	_	20000		$V_{CE} = 3 \text{ V}, I_{C} = 3 \text{ A}^{*1}$
Collector to emitter saturation voltage	$V_{\text{CE(sat)}}$	_	_	1.5	V	$I_{\rm C} = 3 \text{ A}, I_{\rm B} = 6 \text{ mA}^{*1}$
Base to emitter saturation voltage	$V_{BE(sat)}$	_	_	2.0	V	$I_{\rm C} = 3 \text{ A}, I_{\rm B} = 6 \text{ mA}^{*1}$
C to E diode forward current	V_{D}	_	_	3.5	V	I _D = 5 A

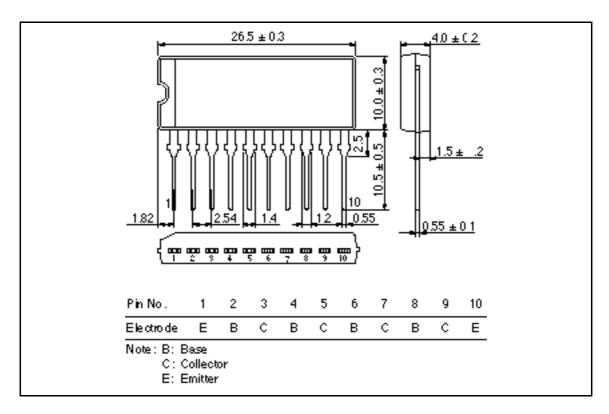
Note: 1. Pulse test.







Unit: mm



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